

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
		Examiner Jennifer Dieterle	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0006149	07-2001	Taniike et al.	204/403
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

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Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/598,001	FUJIWARA ET AL.	
Examiner		Art Unit		Page 1 of 1
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,599,407	07-2003	Taniike et al.	204/403.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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